



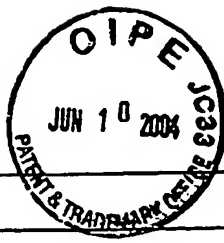
Form PTO-1449 (Substitute)  <b>Information Disclosure Statement</b> <b>BY APPLICANT</b> (Use several sheets if necessary)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number <b>LAZE-01011US1</b>	Serial/Patent Number <b>10/684,883</b>
	Applicant/Patent Owner <b>Thomas F. Rust</b>		
	Filing/Issue Date <b>10/14/2003</b>	Group Art Unit <b>2655</b>	

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	2	4,575,822	03/11/86	Quate	365	174	02/15/83
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	7	4,962,480	10/09/90	Ooumi et al.	365	151	09/12/88
	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
	9	5,038,322	08/06/91	Van Loenen	365	114	02/03/89
	10	5,043,578	08/27/91	Guethner et al.	250	307	04/05/90
	11	5,051,977	09/24/91	Goldberg	369	126	08/30/89
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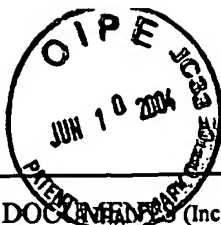
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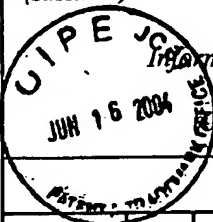
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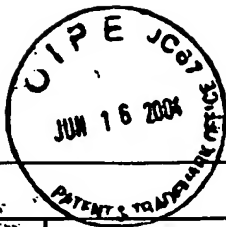


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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		
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